

Notice of References Cited

Application/Control Number
09/675,637
Applicant(s)/Patent Under
Reexamination
YAMANISHI ET AL.

Examiner
Ayal I Sharon

Art Unit
2123
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2004/0015458	01-2004	Takeuchi et al.	706/14
	B	US-2003/0055600	03-2003	Takeuchi, Jun-Ichi	702/181
	C	US-2003/0004902	01-2003	Yamanishi et al.	706/1
	D	US-6,466,894	10-2002	Takeuchi et al.	702/181
	E	US-5,813,002	09-1998	Agrawal et al.	707/5
	F	US-5,832,182	11-1998	Zhang et al.	706/50
	G	US-6,003,029	12-1999	Agrawal et al.	707/7
	H	US-6,055,491	04-2000	Biliris et al.	702/176
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Yamanishi, K. et al. "On-line Unsupervised Outlier Detection Using Finite Mixtures With Discounting Lerning Algorithms". Proc. of the 6th ACM SIGKDD. pp.320-324. 2000.
	V	Fawcett, T. et al. "Activity Monitoring: Noticing Interesting Changes in Behavior". Proc. 5th ACM SIGKDD. pp.53-62. 1999.
	W	Bonchi, F. et al. "A Classification-Based Methodology for Planning Audit Strategies in Fraud Detection". Proc. 5th ACM SIGKDD. pp.175-184. 1999.
	X	Lane, L. et al. "Temporal Sequence Learning and Data Reduction for Anomaly Detection". ACM TISSEC. pp.295-331. 1999.

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Lee, Wenke et al. "Mining in a Data-Flow Environment: Experience in NEtwork Intrusion Detection". Proc. 5th ACM SIGKDD. pp.114-124. 1999.
	V	Rosset, S. et al. "Discovery of Fraud Rules for Telecommunications - CHallenges and Solutions". Proc. 5th ACM SIGKDD. pp.409-413. 1999.
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

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